Search Notes

Application/Control No.	Applicant(s)/P Reexaminatio
	I

10/792,169

Examiner

Christopher S. Kim

Applicant(s)/Patent under
Reexamination
COLDREN ET AL.
Art Unit
3752

SEARCHED				
Class	Subclass	Date	Examiner	
239	88	7/31/2007	СК	
-		-		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	:			

(INCLUDING SEARCI	DATE	EXMR
	DATE	EVINIK
<del></del> =		
		-
		1
		}
•		İ
	į	į
		ļ